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#### 1. General description

Planar passivated SCR with sensitive gate in a TO252 (DPAK) surface mountable plastic package. These devices are intended to be interfaced directly to microcontrollers, logic integrated circuits and other low power gate trigger circuits.

#### 2. Features and benefits

- Sensitive gate
- · Planar passivated for voltage ruggedness and reliability
- Direct triggering from low power drivers and logic ICs
- Surface mountable package

#### 3. Applications

- General purpose switching
- Protection Circuits

#### 4. Quick reference data

reference data						
Parameter	Conditions		Min	Тур	Max	Unit
repetitive peak off- state voltage		[1]	-	-	600	V
repetitive peak reverse voltage			-	-	600	V
average on-state current	half sine wave; T <sub>mb</sub> ≤ 111 °C; <u>Fig. 1</u>		-	-	2.5	A
RMS on-state current	half sine wave; T <sub>mb</sub> ≤ 111 °C; <u>Fig. 2;</u> <u>Fig. 3</u>		-	-	4	A
non-repetitive peak on- state current	half sine wave; T <sub>j(init)</sub> = 25 °C; t <sub>p</sub> = 10 ms; <u>Fig. 4; Fig. 5</u>		-	-	35	A
	half sine wave; T <sub>j(init)</sub> = 25 °C; t <sub>p</sub> = 8.3 ms		-	-	38	A
junction temperature		<u>[2]</u>	-	-	125	°C
eristics						
gate trigger current	V <sub>D</sub> = 12 V; I <sub>T</sub> = 0.1 A; T <sub>j</sub> = 25 °C; <u>Fig. 7</u>		-	15	200	μA
acteristics						
rate of rise of off-state voltage	$V_{DM}$ = 402 V; T <sub>j</sub> = 125 °C; R <sub>GK</sub> = 100 Ω; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; Fig. 12		-	50	-	V/µs
	Parameter         repetitive peak off-         state voltage         repetitive peak reverse         voltage         average on-state         current         RMS on-state current         non-repetitive peak on-         state current         junction temperature         eristics         gate trigger current         acteristics         rate of rise of off-state	ParameterConditionsrepetitive peak off- state voltagerepetitive peak reverse voltageaverage on-state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$ ; Fig. 1RMS on-state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$ ; Fig. 2; Fig. 3non-repetitive peak on- state currenthalf sine wave; $T_{j(init)} = 25 ^{\circ}C$ ; $t_p = 10 ^{o}ms; Fig. 4; Fig. 5non-repetitive peak on-state currenthalf sine wave; T_{j(init)} = 25 ^{\circ}C;t_p = 8.3 ^{o}msjunction temperatureeristicsgate trigger currentV_D = 12 ^{o}V; I_T = 0.1 ^{o}A; T_j = 25 ^{\circ}C; Fig. 7acteristicsrate of rise of off-statevoltageV_{DM} = 402 ^{o}V; T_j = 125 ^{\circ}C; R_{GK} = 100 ^{o}C;(V_{DM} = 67\% ^{o}OV_{DRM}); exponential$	ParameterConditionsrepetitive peak off- state voltage[1]repetitive peak reverse voltage[1]average on-state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$ ; Fig. 1RMS on-state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$ ; Fig. 2; Fig. 3non-repetitive peak on- state currenthalf sine wave; $T_{j(init)} = 25 ^{\circ}C$ ; $t_p = 10  ms; Fig. 4; Fig. 5non-repetitive peak on-state currenthalf sine wave; T_{j(init)} = 25 ^{\circ}C;t_p = 8.3  msjunction temperature[2]eristics[2]gate trigger currentV_D = 12 ^{\circ}V; I_T = 0.1 ^{\circ}A; T_j = 25 ^{\circ}C; Fig. 7acteristicsV_{DM} = 402 ^{\circ}V; T_j = 125 ^{\circ}C; R_{GK} = 100 ^{\circ}\Omega;(V_{DM} = 67\% of V_{DRM}); exponential$	ParameterConditionsMinrepetitive peak off- state voltage[1]-repetitive peak reverse voltage[1]-average on-state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$ ; Fig. 1-RMS on-state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$ ; Fig. 2; Fig. 3-non-repetitive peak on- state currenthalf sine wave; $T_{mb} \le 111 ^{\circ}C$ ; Fig. 2; Fig. 3-non-repetitive peak on- state currenthalf sine wave; $T_{j(init)} = 25 ^{\circ}C$ ; $t_p = 10 ^{\circ}ms; Fig. 4; Fig. 5-number of the peak on-state currenthalf sine wave; T_{j(init)} = 25 ^{\circ}C;t_p = 8.3 ^{\circ}ms-junction temperature[2]-gate trigger currentV_D = 12 ^{\circ}V; ^{\circ}I_T = 0.1 ^{\circ}A; ^{\circ}I_T = 25 ^{\circ}C; ^{\circ}E_T, I_T = 0.1 ^{\circ}A; I_T = 25 ^{\circ}C; I_T = 0.1 ^{\circ}A; I_T = 25 ^{\circ}C; I_T = 0.1 ^{\circ}A; I_T = 25 ^{\circ}C; I_T = 0.1 ^{\circ}A; I_T = 0.1$	$\begin{array}{ c c c c } \hline Parameter & Conditions & Min & Typ \\ \hline Parameter & Interpretative peak off-state voltage & Interpretative peak reverse \\ repetitive peak reverse & Interpretative peak reverse \\ voltage & Interpretative peak reverse \\ voltage & Interpretative peak reverse \\ voltage & Interpretative peak reverse \\ repetitive peak reverse & Interpretative peak reverse \\ RMS on-state current & half sine wave; T_{mb} \leq 111 \ ^{\circ}C; \ Fig. 1 & Interpretative peak reverse \\ RMS on-state current & half sine wave; T_{mb} \leq 111 \ ^{\circ}C; \ Fig. 2; & Interpretative peak reverse \\ \hline RMS on-state current & half sine wave; T_{j(init)} = 25 \ ^{\circ}C; & Interpretative peak on-state current \\ \hline Interpretative peak on-state current & half sine wave; T_{j(init)} = 25 \ ^{\circ}C; & Interpretative peak reverse \\ \hline Interpretative peak on-state current & Interpretative peak on-state current \\ \hline Interpretative peak on-state current & half sine wave; T_{j(init)} = 25 \ ^{\circ}C; & Interpretative peak reverse \\ \hline Interpretative peak on-state current & Interpretative peak reverse \\ \hline Interpretative peak on-state reverse & Interpretative peak reverse \\ \hline Interpretative peak on-state reverse \\ \hline Interpr$	$\begin{array}{ c c c c c } \hline Parameter & Conditions & Min & Typ & Max \\ \hline repetitive peak off-state voltage & & & & & & & & & & & & & & & & & & &$

- Although not recommended, off-state voltages up to 800V may be applied without damage, but the thyristor may switch to the on-state. The rate of rise of current should not exceed 15 A/µs.
- [2] Operation above  $110^{\circ}$ C may require the use of a gate to cathode resistor of  $1k\Omega$  or less.

#### 5. Pinning information

Table 2. F	Pinning inf	ormation		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	К	cathode	mb	А <del>-Ң</del> К
2	А	anode[1]		G sym037
3	G	gate		Syntosi
mb	A	mounting base; connected to anode	DPAK (TO252N)	

[1] It is not possible to connect to pin 2 of the TO252 package.

## 6. Ordering information

#### Table 3. Ordering information

Type number	Package	9						
	Name	Description	Version					
BT150S-600R	DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	TO252N					

#### 7. Marking

Table 4. Marking codes	
Type number	Marking code
BYV10ED-600P	BYV10ED-600P

#### 8. Limiting values

#### Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V <sub>DRM</sub>	repetitive peak off-state voltage		[1]	-	600	V
V <sub>RRM</sub>	repetitive peak reverse voltage			-	600	V
I <sub>T(AV)</sub>	average on-state current	half sine wave; T <sub>mb</sub> ≤ 111 °C; <u>Fig. 1</u>		-	2.5	А
I <sub>T(RMS)</sub>	RMS on-state current	half sine wave; T <sub>mb</sub> ≤ 111 °C; <u>Fig. 2;</u> <u>Fig. 3</u>		-	4	A
I <sub>TSM</sub>	non-repetitive peak on- state current	half sine wave; T <sub>j(init)</sub> = 25 °C; t <sub>p</sub> = 10 ms; Fig. 4; Fig. 5		-	35	A
		half sine wave; T <sub>j(init)</sub> = 25 °C; t <sub>p</sub> = 8.3 ms		-	38	А
l <sup>2</sup> t	I <sup>2</sup> t for fusing	t <sub>p</sub> = 10 ms; SIN		-	6.1	A²s
dl <sub>T</sub> /dt	rate of rise of on-state current	$I_T$ = 10 A; $I_G$ = 50 mA; $dI_G/dt$ = 50 mA/µs		-	50	A/µs
I <sub>GM</sub>	peak gate current			-	2	А
V <sub>RGM</sub>	peak reverse gate voltage			-	5	V
P <sub>GM</sub>	peak gate power			-	5	W
P <sub>G(AV)</sub>	average gate power	over any 20 ms period		-	0.5	W
T <sub>stg</sub>	storage temperature			-40	150	°C
Tj	junction temperature		[2]	-	125	°C

[1] Although not recommended, off-state voltages up to 800V may be applied without damage, but the thyristor may switch to the on-state. The rate of rise of current should not exceed 15 A/ $\mu$ s. Operation above 110°C may require the use of a gate to cathode resistor of 1k $\Omega$  or less.

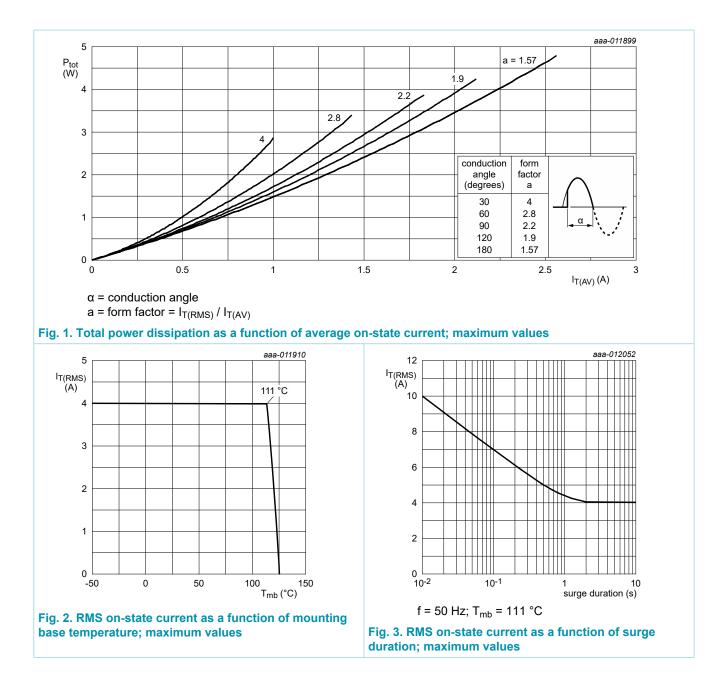
[2]

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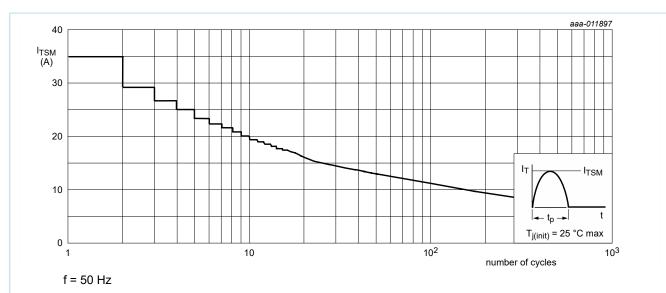
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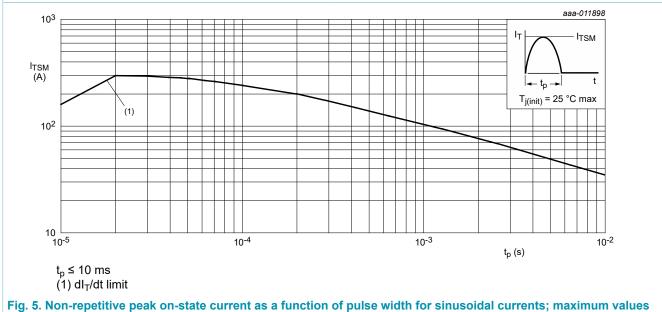
#### **WeEn Semiconductors**

## BT150S-600R

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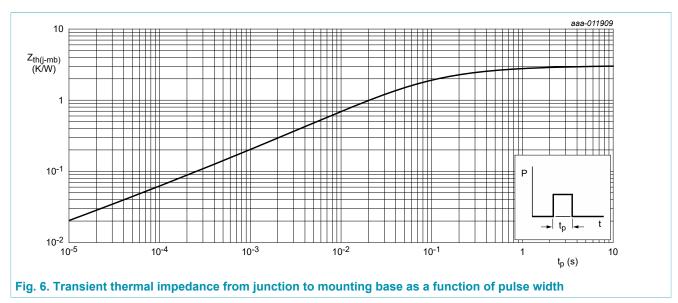






#### 9. Thermal characteristics

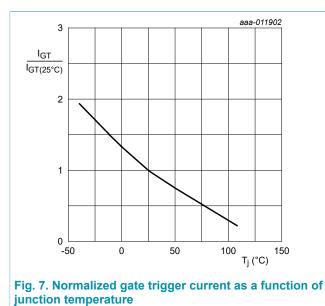
Table 6. The	rmal characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	<u>Fig. 6</u>	-	-	3	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient free air	Device mounted on an FR4 Printed- Circuit Board (PCB), single-sided copper, tin-plated and standard footprint	-	75	-	K/W

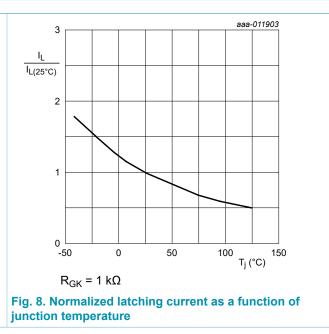


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#### **10. Characteristics**

Symbol	Parameter	Conditions	N	lin	Тур	Max	Unit
Static chara	octeristics						
I <sub>GT</sub>	gate trigger current	V <sub>D</sub> = 12 V; I <sub>T</sub> = 0.1 A; T <sub>j</sub> = 25 °C; <u>Fig. 7</u>	-		15	200	μA
IL	latching current	$V_D$ = 12 V; I <sub>G</sub> = 0.1 A; T <sub>j</sub> = 25 °C; <u>Fig. 8</u>	-		0.17	10	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-		0.1	6	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 5 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-		1.23	1.8	V
V <sub>GT</sub>	gate trigger voltage	V <sub>D</sub> = 12 V; I <sub>T</sub> = 0.1 A; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>	-		0.4	1	V
		V <sub>D</sub> = 600 V; I <sub>T</sub> = 0.1 A; T <sub>j</sub> = 110 °C; <u>Fig. 11</u>	0	.1	0.2	-	V
I <sub>D</sub>	off-state current	V <sub>D</sub> = 600 V; T <sub>j</sub> = 125 °C	-		0.1	0.5	mA
I <sub>R</sub>	reverse current	V <sub>R</sub> = 600 V; T <sub>j</sub> = 125 °C	-		0.1	0.5	mA
Dynamic ch	aracteristics						
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$\label{eq:VDM} \begin{array}{l} V_{DM} = 402 \; V; \; T_{j} = 125 \; ^{\circ}\text{C}; \; R_{GK} = 100 \; \Omega; \\ (V_{DM} = 67\% \; of \; V_{DRM}); \; exponential \\ waveform; \; \underline{Fig. 12} \end{array}$	-		50	-	V/µs
t <sub>gt</sub>	gate-controlled turn-on time	$\begin{split} I_{TM} &= 10 \text{ A}; \text{ V}_{D} = 600 \text{ V}; \text{ I}_{G} = 5 \text{ mA}; \text{ dI}_{G} \text{/} \\ \text{dt} &= 0.2 \text{ A} \text{/} \mu \text{s}; \text{ T}_{j} = 25 ^{\circ} \text{C} \end{split}$	-		2	-	μs
t <sub>q</sub>	commutated turn-off time		-		100	-	μs

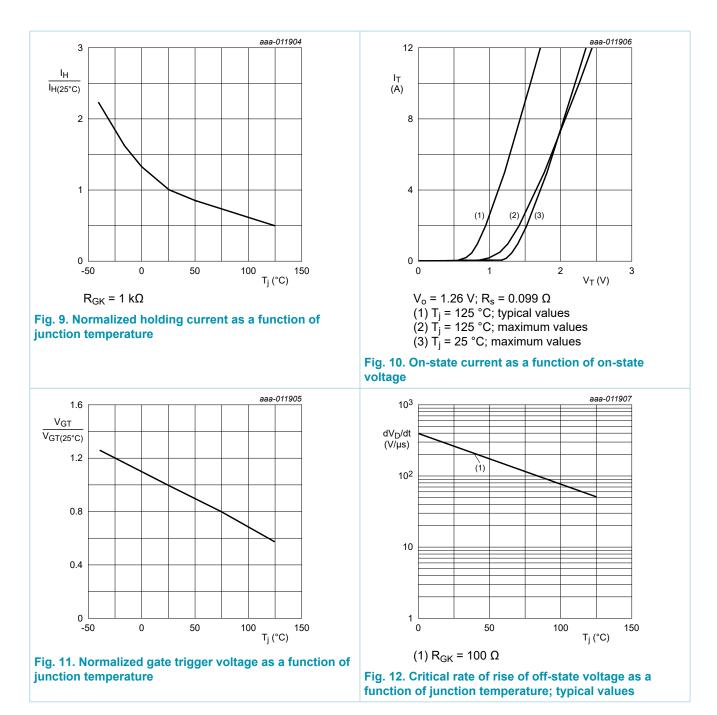




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#### **11. Package outline**

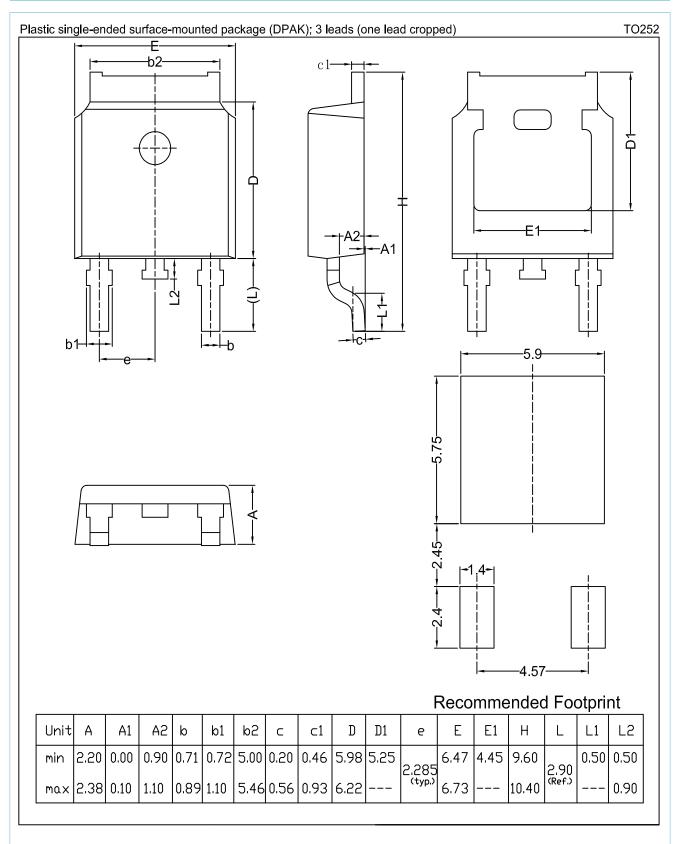


Fig. 13. Package outline DPAK (TO252N)
BT150S-600R
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#### 12. Legal information

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Document status [1][2]	Product status [ <u>3]</u>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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BT150S-600R

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